

FEATURES

- Controlled Baseline
 - One Assembly/Test Site, One Fabrication Site
- Extended Temperature Performance of –55°C to 125°C
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree (1)
- 2-V to 6-V V_{CC} Operation
- Inputs Accept Voltages to 6 V
- Max t_{pd} of 7.5 ns at 5 V
- (1) Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

DW OR NS PACKAGE (TOP VIEW) 20 V_{CC} 1<u>OE</u> 1A1 2 19 20E 2Y4 **[**]3 18 1Y1 1A2 [17**∏** 2A4 2Y3 5 16**∏** 1Y2 1A3 6 15 2A3 2Y2 14**∏** 1Y3 8 1A4 13 Π 2A2 2Y1 9 12**∏** 1Y4 **GND** 10 11 1 2A1

DESCRIPTION

This octal buffer and line driver is designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The SN74AC244-EP device is organized as two 4-bit buffers/drivers with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes noninverted data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

ORDERING INFORMATION

T _A	PACK	AGE ⁽¹⁾	ORDERABLE PART NUMBER	TOP-SIDE MARKING	
FE°C to 125°C	SOIC - DW	Tape and reel	SN74AC244MDWREP	SAC244MEP	
–55°C to 125°C	SOP - NS	Tape and reel	SN74AC244MNSREP	SAC244MEP	

(1) Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE (EACH BUFFER)

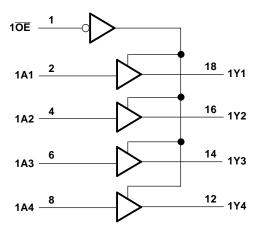
INPU	JTS	OUTPUT
ŌĒ	Α	Y
L	Н	Н
L	L	L
Н	X	Z

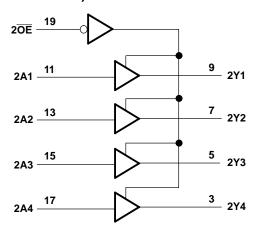


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LOGIC DIAGRAM (POSITIVE LOGIC)





Absolute Maximum Ratings⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V_{CC}	Supply voltage range		-0.5	7	V
VI	Input voltage range (2)		-0.5	V _{CC} + 0.5	V
Vo	Output voltage range ⁽²⁾		-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	$V_I < 0 \text{ or } V_I > V_{CC}$		±20	mA
I _{OK}	Output clamp current	$V_O < 0$ or $V_O > V_{CC}$		±20	
Io	Continuous output current	$V_O = 0$ to V_{CC}		±50	mA
	Continuous current through V _{CC} or GND			±200	mA
0	Dackage thermal impedance (3)	DW package		58	°C ///
θ_{JA}	Package mermai impedance (%)	thermal impedance (3) DW package 58 NS package 60	°C/W		
T _{stg}	Storage temperature range ⁽⁴⁾		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

⁽²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

⁽³⁾ The package thermal impedance is calculated in accordance with JESD 51-7.

⁽⁴⁾ Long-term high-temperature storage and/or extended use at maximum recommended operating conditions may result in a reduction of overall device life. See http://www.ti.com/ep_quality for additional information on enhanced plastic packaging.

SN74AC244-EP OCTAL BUFFER/DRIVER WITH 3-STATE OUTPUTS

Recommended Operating Conditions⁽¹⁾

			MIN	MAX	UNIT
V_{CC}	Supply voltage		2	6	V
		$V_{CC} = 3 V$	2.1		
V_{IH}	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15		V
		$V_{CC} = 5.5 \text{ V}$	3.85		
		$V_{CC} = 3 V$		0.9	
V_{IL}	Low-level input voltage	$V_{CC} = 4.5 \text{ V}$		1.35	V
		$V_{CC} = 5.5 \text{ V}$		1.65	
V_{I}	Input voltage		0	V_{CC}	V
V_{O}	Output voltage		0	V_{CC}	V
		V _{CC} = 3 V		-12	
I_{OH}	High-level output current	$V_{CC} = 4.5 \text{ V}$		-24	mA
		$V_{CC} = 5.5 \text{ V}$		-24	
		$V_{CC} = 3 V$		12	
I_{OL}	Low-level output current	$V_{CC} = 4.5 \text{ V}$		24	mA
		$V_{CC} = 5.5 \text{ V}$		24	
Δt/Δν	Input transition rise or fall rate			8	ns/V
T _A	Operating free-air temperature		-55	125	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

	DADAMETED	TEST CONDITIONS	V	T,	_A = 25°C	MINI MAY	LINUT	
	PARAMETER	TEST CONDITIONS	v_{cc}	MIN	TYP MAX	MIN MAX	UNIT	
			3 V	2.9		2.9		
		I _{OH} = -50 μA	4.5 V	4.4		4.4		
V			5.5 V	5.4		5.4	V	
V _{OH}		$I_{OH} = -12 \text{ mA}$	3 V	2.56		2.4	V	
		I _{OH} = -24 mA	4.5 V	3.86		3.7		
		1 _{OH} = -24 IIIA	5.5 V	4.86		4.7		
			3 V		0.1	0.1		
		$I_{OL} = 50 \mu A$	4.5 V		0.1	0.1	V	
V			5.5 V		0.1	0.1		
V_{OL}		I _{OL} = 12 mA	3 V		0.36	0.5	V	
		I _{OL} = 24 mA	4.5 V		0.36	0.5		
		1 _{OL} = 24 mA	5.5 V		0.36	0.5		
	Data inputs	$V_I = V_{CC}$ or GND	5.5 V		±0.1	±1		
l _l	Control inputs	$V_I = V_{CC}$ or GND	3.5 V		±0.1	±1	μΑ	
I_{OZ}	·	$V_O = V_{CC}$ or GND, $V_{I(OE)} = V_{IL}$ or V_{IH}	5.5 V		±0.25	±5	μΑ	
I_{CC}		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V		4	80	μΑ	
C_{i}		$V_I = V_{CC}$ or GND	5 V		2.5		pF	



Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	ТО	T,	չ = 25°C		MIN	MAX	UNIT
PARAWETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV	IVIAA	
t _{PLH}	Δ.	V	2	6.5	9	1	12.5	ns
t _{PHL}	A	T	2	6.5	9	1	12	
t _{PZH}	 OE	V	2	6	10.5	1	11.5	no
t _{PZL}	OE OE	T	2.5	7.5	10	1	13	ns
t _{PHZ}	 OE	V	3	7	10	1	12.5	
t _{PLZ}	J	ř	2.5	7.5	10.5	1	13	ns

Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 5.5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	4 = 25°C		MIN	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIN		
t _{PLH}	^	V	1.5	5	7	1	9.5	ns
t _{PHL}	Α	Ť	1.5	5	7	1	9	
t _{PZH}	- OE	V	1.5	5	7	1	9	
t _{PZL}	- OE	ř	1.5	5.5	8	1	10.5	ns
t _{PHZ}	- OE	V	2.5	6.5	9	1	10.5	
t _{PLZ}	- OE	ř	2	6.5	9	1	11	ns

Operating Characteristics

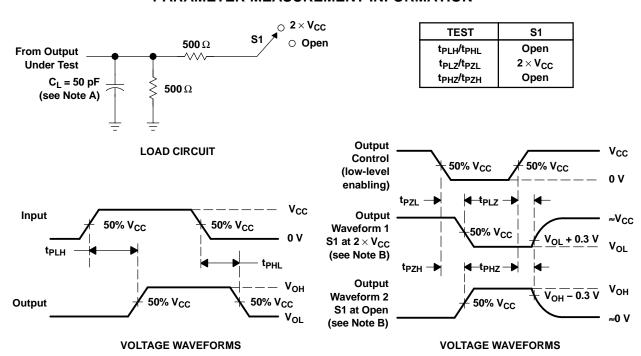
 $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C_{pd}	Power dissipation capacitance per buffer/driver	C _L = 50 pF, f = 1 MHz	45	pF

SN74AC244-EP



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50~\Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time, with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
SN74AC244MDWREP	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	SAC244MEP
SN74AC244MDWREP.A	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	SAC244MEP
SN74AC244MNSREP	Last	Production	SOP (NS) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	SAC244MEP
	Time Buy								
V62/04622-01XE	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	SAC244MEP
V62/04622-01YE	Last	Production	SOP (NS) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	SAC244MEP
	Time Buy								

⁽¹⁾ Status: For more details on status, see our product life cycle.

- (3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.
- (4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.
- (6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.





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OTHER QUALIFIED VERSIONS OF SN74AC244-EP:

■ Catalog : SN74AC244

• Automotive : SN74AC244-Q1

• Military : SN54AC244

NOTE: Qualified Version Definitions:

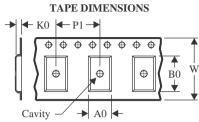
- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

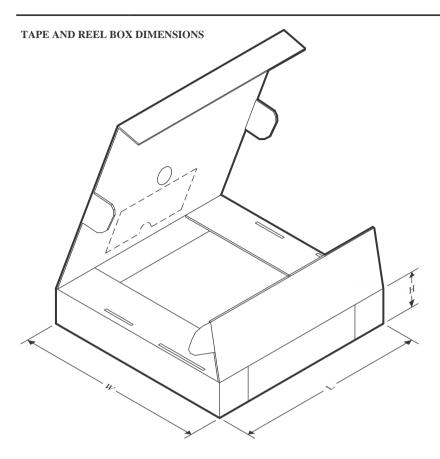
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AC244MDWREP	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN74AC244MNSREP	SOP	NS	20	2000	330.0	24.4	8.4	13.0	2.5	12.0	24.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AC244MDWREP	SOIC	DW	20	2000	356.0	356.0	45.0
SN74AC244MNSREP	SOP	NS	20	2000	356.0	356.0	45.0

MECHANICAL DATA

NS (R-PDSO-G**)

14-PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



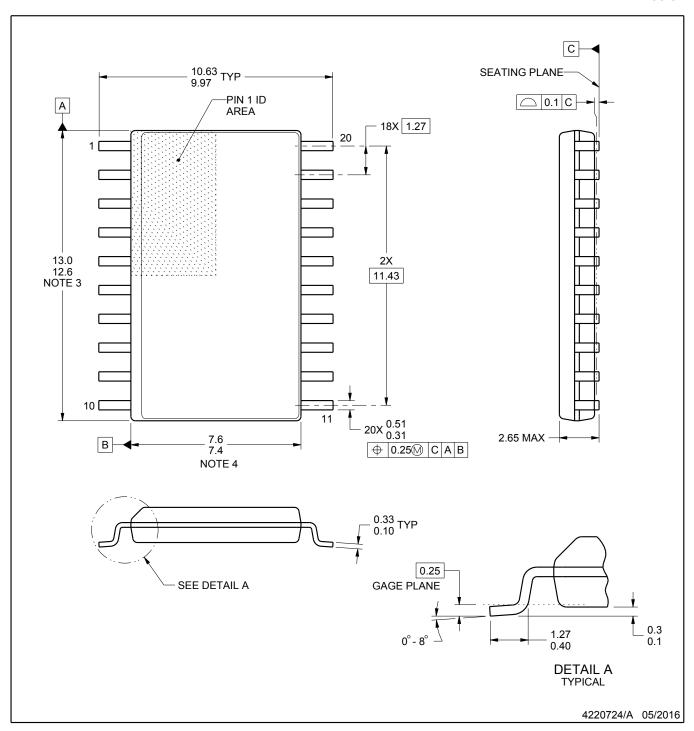
NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.





SOIC



NOTES:

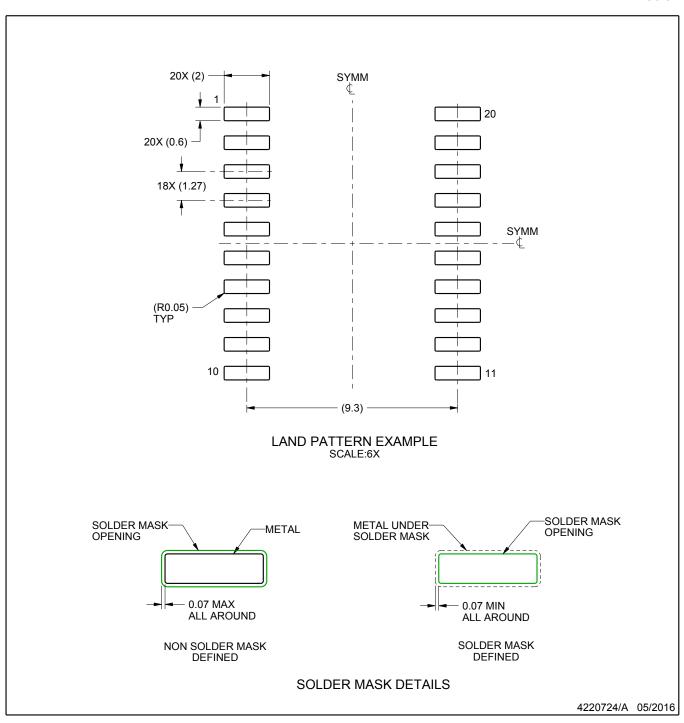
- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



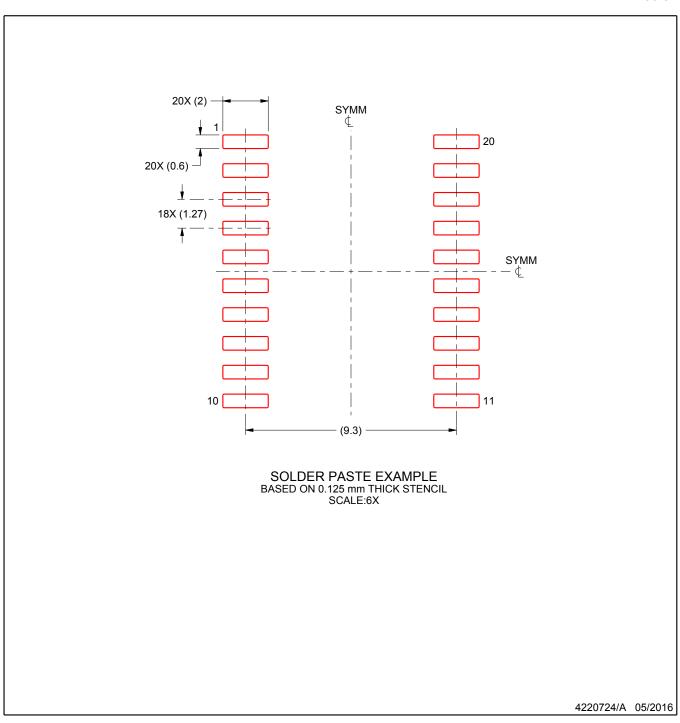
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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